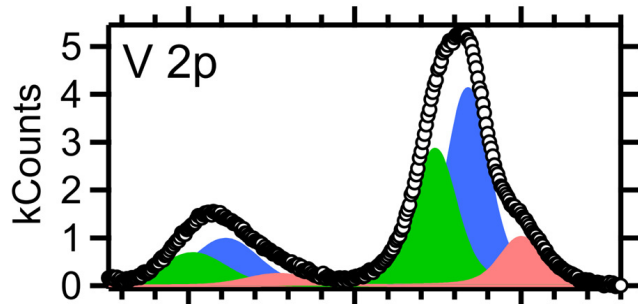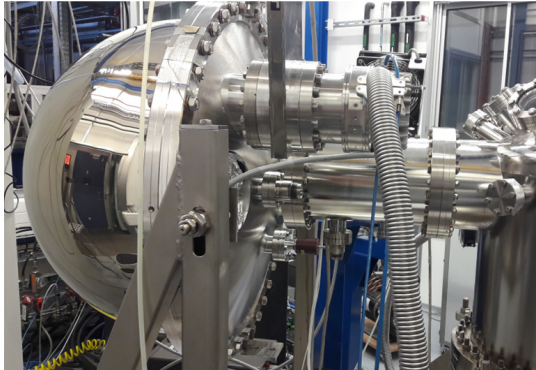# X-Ray Photoemission Spectroscopy: Processing, fitting and analyzing data acquired with synchrotron light


Instructors: Julien Rault (Cassiopee) and Mathieu Silly (Tempo)

Schedule : Friday, January 19, 3pm to 6pm

Location: SOLEIL, Building T5

The aim of this tutorial is to give first-hand experience on X-ray Photoelectron Spectroscopy (XPS) data processing and analysis, focusing on the specificities offered by synchrotron light. A brief introduction will present the data acquisition and the very first data treatments, followed by two practical case studies on Soleil computers:

- Low energy XPS – Surfaces and 2D materials
  Identification of surface / interface components using variable energies.

- High energy XPS (HAXPES) – Buried interfaces
  Potential / charge profile via angle-dependent experiments.
  Chemical depth profile using standing-wave methods.
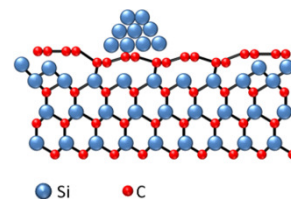
This tutorial should help users be more autonomous to analyze their XPS data but also in submitting proposals to XPS/HAXPES beamlines in synchrotron facilities.

The number of participants is limited to 20 people.